



# USBULC6-2F3

IPAD™

Dual ultra low capacitance protection for high speed USB

## Main application

- Hi-Speed USB port in wireless handsets (up to 480 Mb/s according to USB 2.0 High Speed Specification)

## Features

- Ultra low diode capacitance (1.2 pF max)
- Two data lines (D+ and D-) protected against 15 kV ESD
- Breakdown Voltage  $V_{BR} = 6.0 \text{ V min}$
- Flip-Chip 400  $\mu\text{m}$  pitch, lead-free
- Very low leakage current
- Very small PCB area
- RoHS compliant

## Description

The USBULC6-2F3 is a monolithic, application specific discrete device dedicated to ESD protection of high speed interfaces.

Its ultra low line capacitance secures a high level of signal integrity without compromising the protection of downstream sensitive chips against the most stringently characterized ESD strikes.

## Benefits

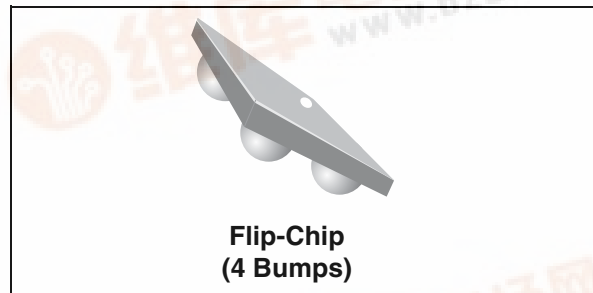
- Minimized impact on rise and fall times for maximum data integrity
- Low PCB space occupation
- Higher reliability offered by monolithic integration

## Complies with the following standards:

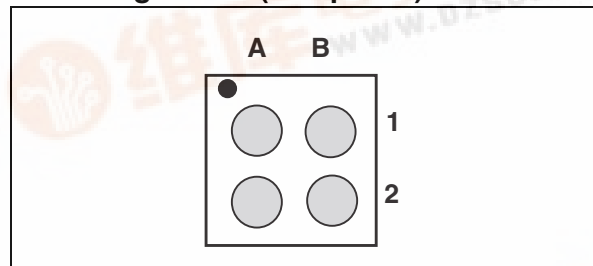
IEC 61000-4-2: 15 kV (air discharge)  
8 kV (contact discharge)

## MIL STD 883G - Method 3015.7

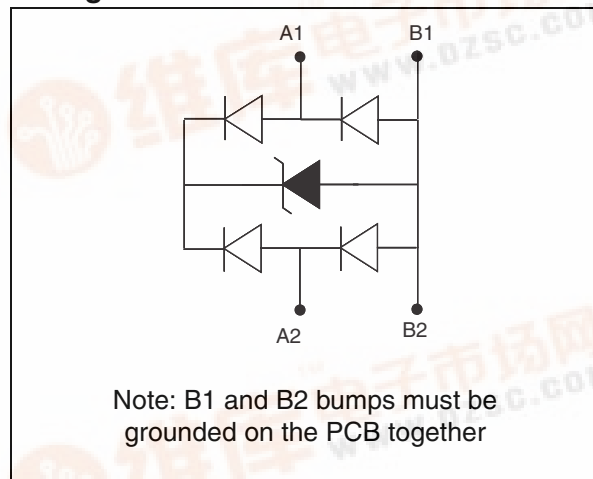
25 kV (Human body model)



## Pin configuration (bump side)



## Configuration



## Order code

Part Number	Marking
USBULC6-2F3	EH

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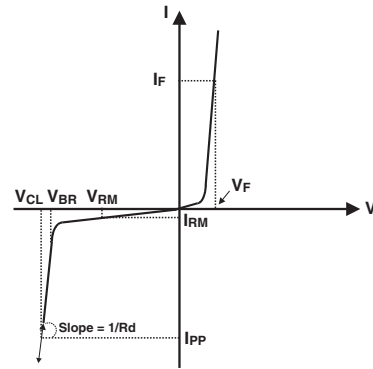
# 1 Characteristics

**Table 1. Absolute Maximum Ratings ( $T_{amb} = 25^{\circ} C$ )**

Symbol	Parameter	Value	Unit
$V_{PP}$	ESD discharge IEC 61000-4-2, air discharge ESD discharge IEC 61000-4-2, contact discharge	15 8	kV
$P_{PP}$	Peak pulse power dissipation (8/20 $\mu s$ )	60	W
$T_j$	Maximum junction temperature	125	$^{\circ} C$
$T_{op}$	Operating temperature range	-30 to + 85	$^{\circ} C$
$T_{stg}$	Storage temperature range	-55 to +150	$^{\circ} C$

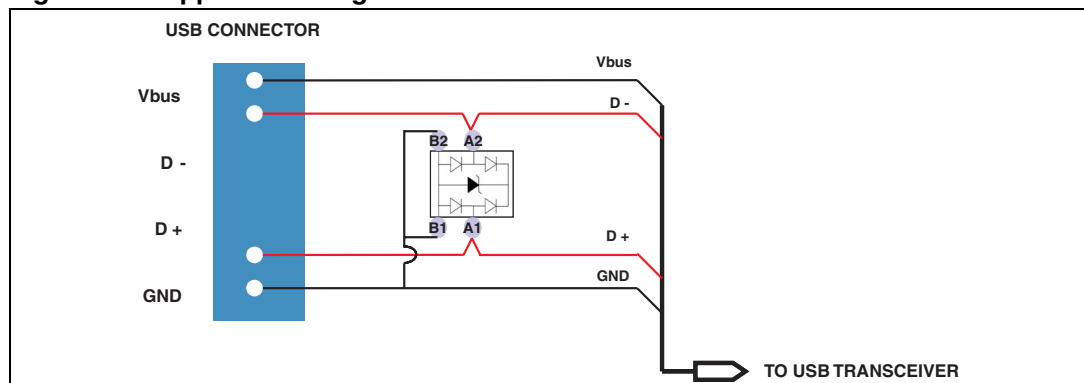
**Table 2. Electrical characteristics ( $T_{amb} = 25^{\circ} C$ )**

Symbol	Parameter
$V_{BR}$	Breakdown voltage
$I_{RM}$	Leakage current @ $V_{RM}$
$V_{RM}$	Stand-off voltage
$V_{CL}$	Clamping voltage
$R_d$	Dynamic impedance
$I_{PP}$	Peak pulse current
$\alpha T$	Voltage temperature coefficient
$V_F$	Forward voltage drop

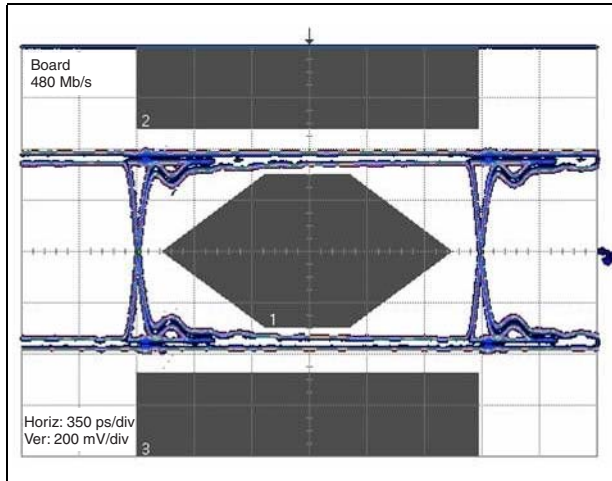


Symbol	Test conditions	Min.	Typ.	Max.	Unit
$V_{BR}$	$I_R = 1 \text{ mA}$	6		9	V
$I_{RM}$	$V_{RM} = 3 \text{ V}$			100	nA
$R_d$	Exponential wave form 8/20 $\mu s$ , $I_{pp} = 1 \text{ to } 5 \text{ A}$		1.6		$\Omega$
$\alpha T$	$I_R = 1 \text{ mA}$			5	$10^{-4}/^{\circ} C$
$C_{line}$	$V_{LINE} = 0 \text{ V}$ , $V_{OSC} = 30 \text{ mV}$ , $F = 1 \text{ MHz}$			1.2	pF

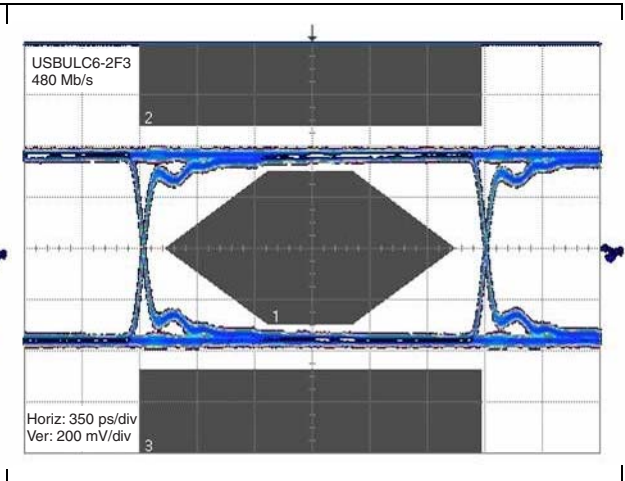
**Figure 1. Application diagram**



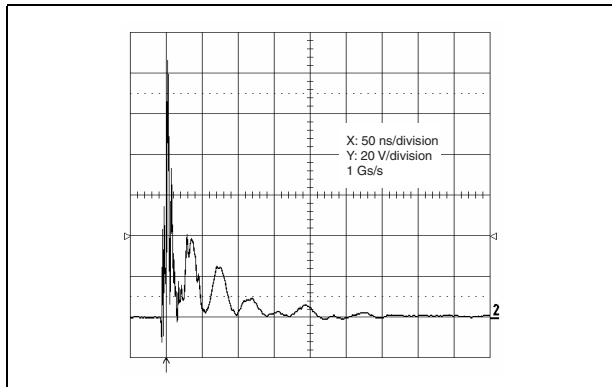
**Figure 2. Eye diagram, board only (according to USB High Speed)**



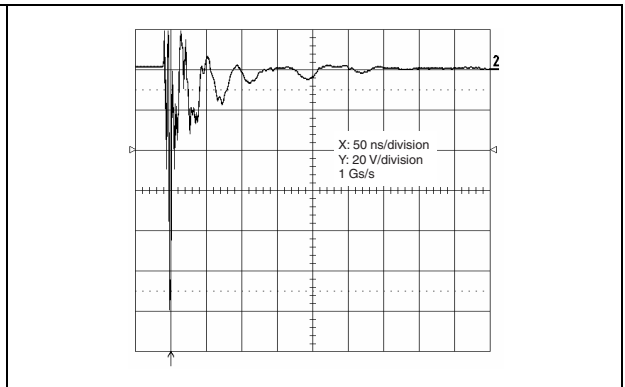
**Figure 3. Eye diagram, board with USBULC6-2F3 (according to USB 2.0 High Speed)**



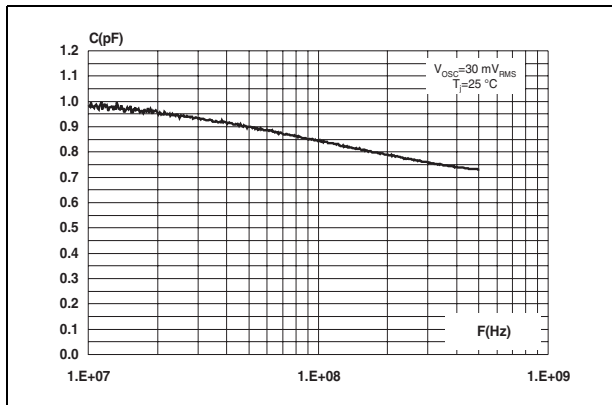
**Figure 4. ESD response to IEC 61000-4-2 (+15 kV air discharge)**



**Figure 5. ESD response to IEC 61000-4-2 (-15 kV air discharge)**



**Figure 6. Junction capacitance versus frequency (typical values)**



**Figure 7. Analog crosstalk measurements**

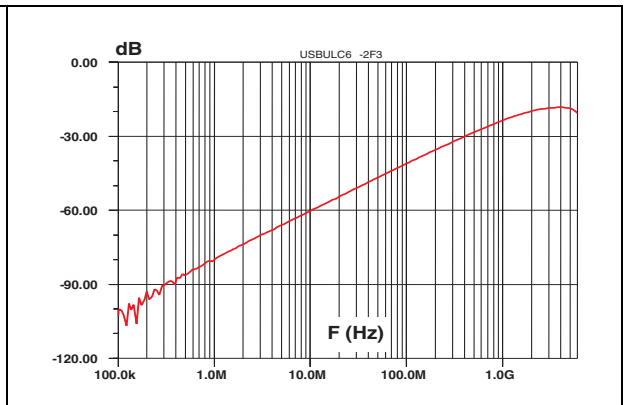


Figure 8. S21 (dB) attenuation measurements

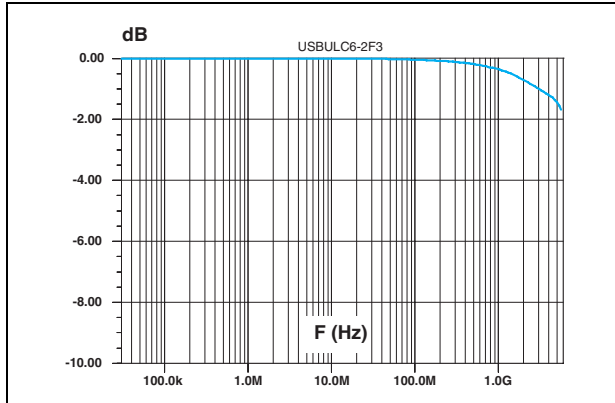


Figure 9. Digital crosstalk

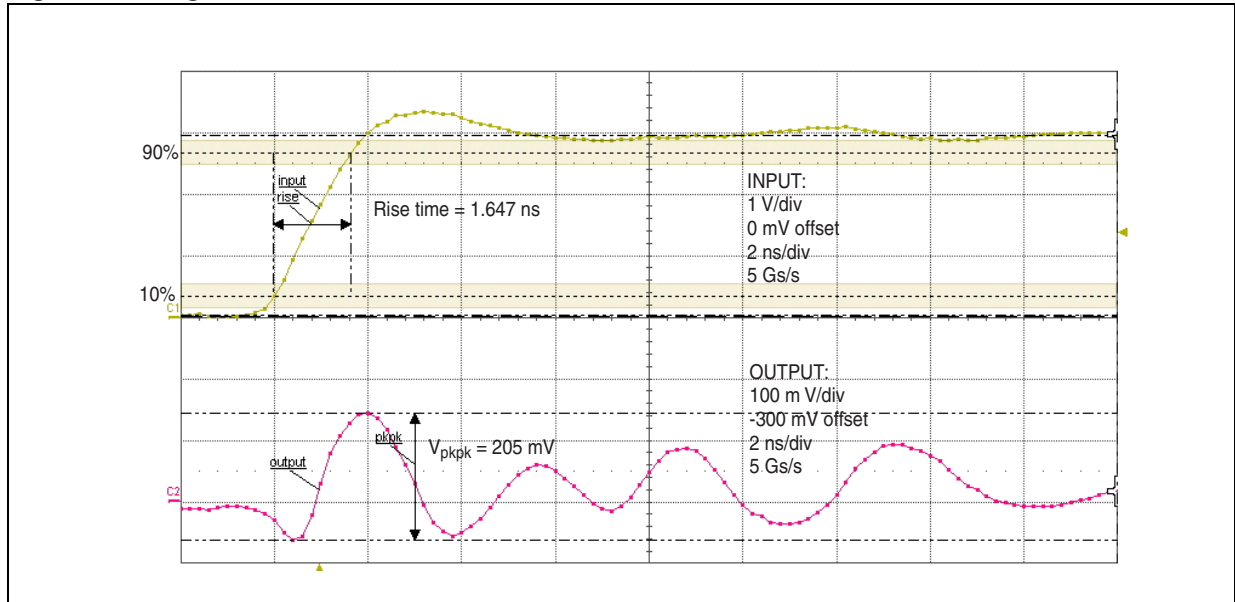


Figure 10. Relative variation of peak pulse power versus initial junction temperature

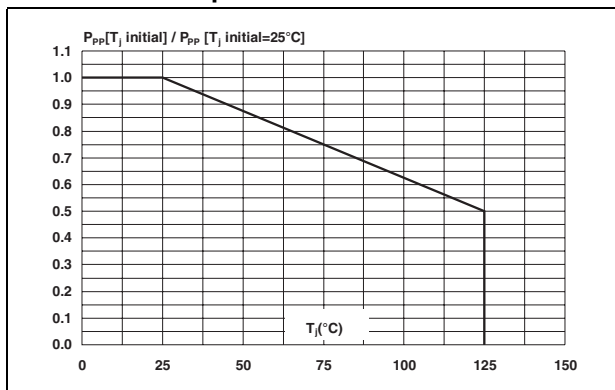


Figure 11. Peak pulse power versus exponential pulse duration

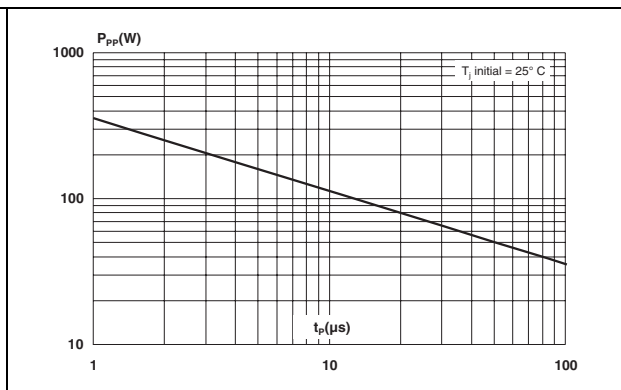


Figure 12. Clamping voltage versus peak pulse current (typical values, exponential waveform)

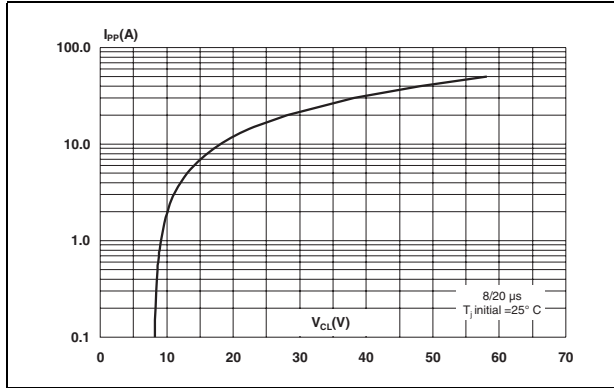
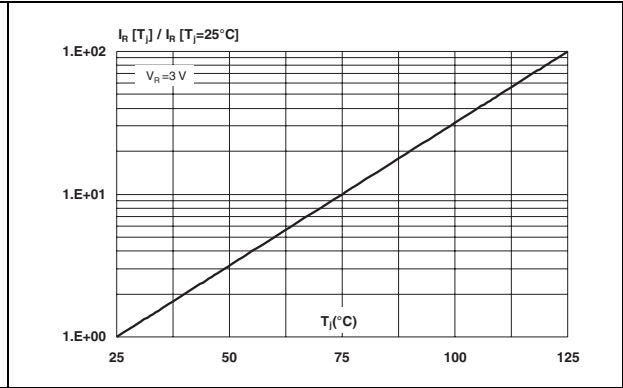
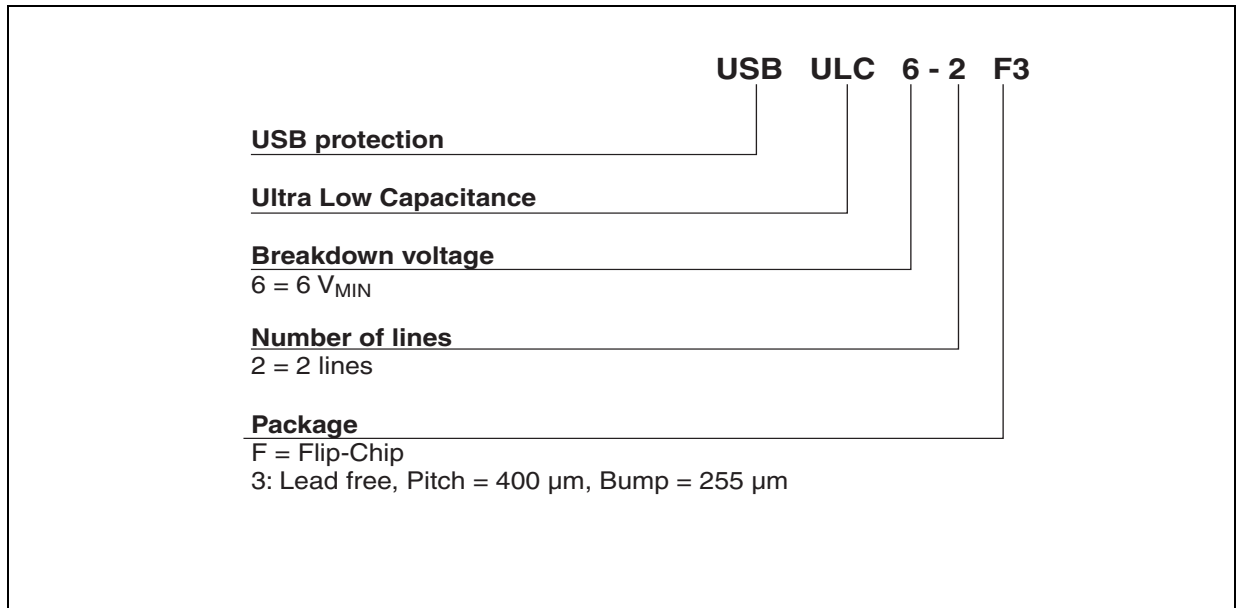


Figure 13. Relative variation of leakage current versus junction temperature (typical values)



## 2 Ordering information scheme



### 3 Package information

Figure 14. Flip-Chip dimensions

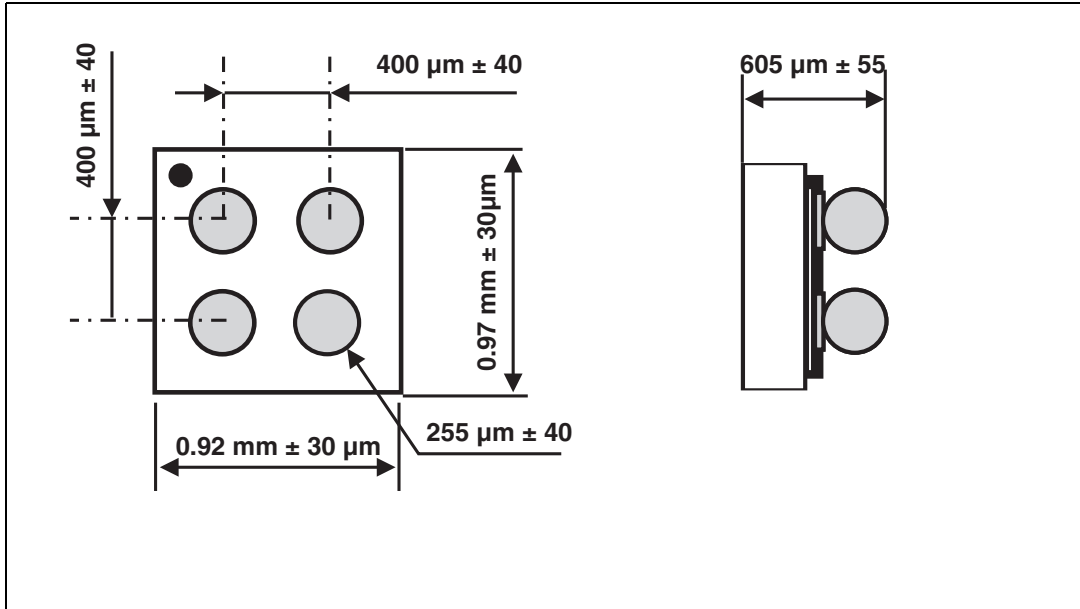


Figure 15. Foot print recommendations Figure 16. Marking

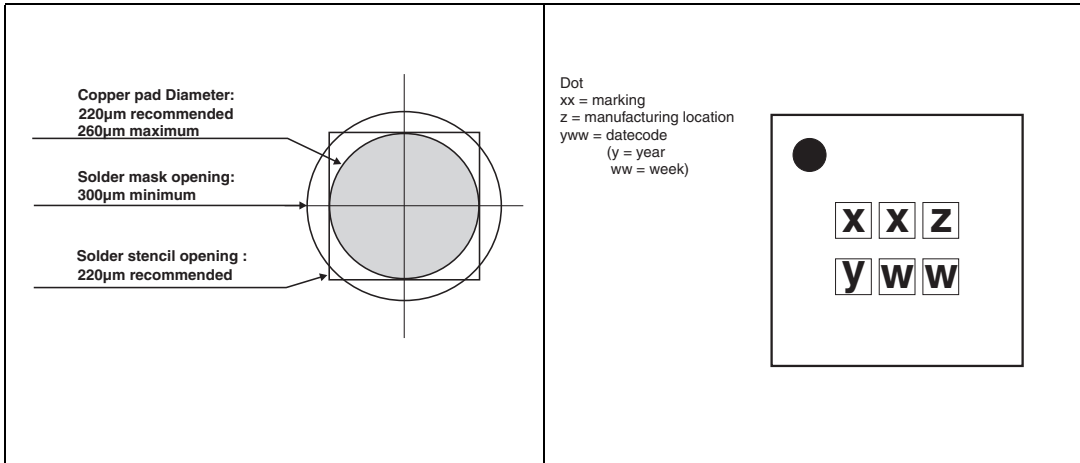
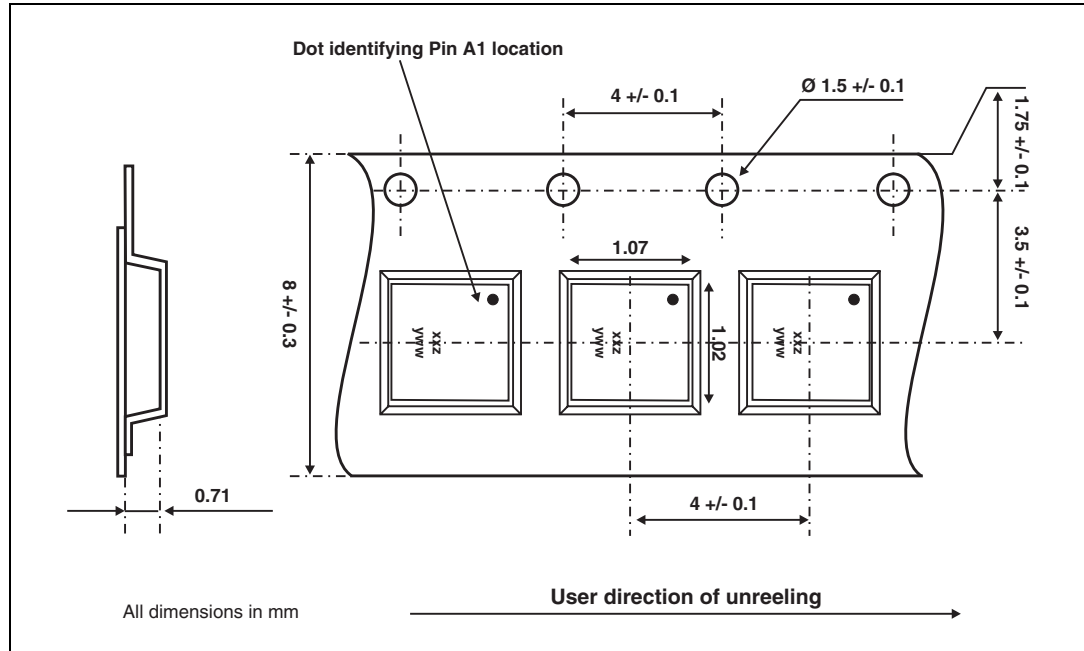


Figure 17. Flip-Chip tape and reel specifications



In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a lead-free second level interconnect. The category of second level interconnect is marked on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: [www.st.com](http://www.st.com).

Note: More information is available in the application notes:  
 AN2348: "400 µm Flip-Chip: Package description and recommendations for use"  
 AN1751: "EMI Filters: Recommendations and measurements"

## 4 Ordering information

Part Number	Marking	Package	Weight	Base qty	Delivery mode
USBULC6-2F3	EH	Flip-Chip	1.16 mg	5000	Tape and reel (7")

## 5 Revision history

Date	Revision	Changes
15-Dec-2006	1	Initial release

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